## Notice of References Cited Application/Control No. 10/668,360 Applicant(s)/Patent Under Reexamination OHYAMA ET AL. Examiner BENJAMIN O. DULANEY 2625 Applicant(s)/Patent Under Reexamination OHYAMA ET AL.

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,005,673 A	12-1999	Murai et al.	358/434
*	В	US-6,069,706 A	05-2000	Kajita et al.	358/1.15
*	С	US-2002/0080250 A1	06-2002	OGAWA et al.	348/232
*	D	US-2002/0156923 A1	10-2002	Tanimoto, Yoshifumi	709/246
*	Е	US-2002/0141380 A1	10-2002	Koguchi, Masatsugu	370/351
*	F	US-2002/0149784 A1	10-2002	Levin et al.	358/1.2
*	G	US-2004/0233484 A1	11-2004	Seko et al.	358/523
*	Н	US-7,352,488 B2	04-2008	Ben-Chorin et al.	358/1.9
	I	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	Ø					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	C					
	>					
	w					
	х					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.